## Notice of References Cited Application/Control No. 10/608,969 Examiner Tianjie Chen Applicant(s)/Patent Under Reexamination GRONSETH ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0227716 A1	12-2003	Yamakura et al.	360/234.7
	В	US-RE30,601	05-1981	Horr et al.	355/76
	С	US-2005/0007699 A1	01-2005	Ohno et al.	360/235.7
	D	US-2004/0179302 A1	09-2004	Sasaki et al.	360/236.3
	Е	US-2003/0231429 A1	12-2003	Boutaghou et al.	360/235.8
	F	US-2003/0174444 A1	09-2003	Mei et al.	360/236.6
	G	US-6,756,287 B2	06-2004	Khlif et al.	438/460
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	х	

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